## Shojan P Pavunny

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Raman spectroscopy and field emission characterization of delafossite CuFeO2. Journal of Applied Physics, 2010, 107, .	2.5	89
2	Dielectric anomalies due to grain boundary conduction in chemically substituted BiFeO3. Journal of Applied Physics, 2015, 117, .	2.5	78
3	Structural, electrical, and magnetic properties of chemical solution deposited BiFe1â^'xTixO3 and BiFe0.9Ti0.05Co0.05O3 thin films. Journal of Applied Physics, 2009, 106, 014103.	2.5	71
4	Ultrahigh capacitive energy storage in highly oriented Ba(ZrxTi1-x)O3 thin films prepared by pulsed laser deposition. Applied Physics Letters, 2017, 111, .	3.3	51
5	Multilevel unipolar resistive memory switching in amorphous SmGdO3 thin film. Applied Physics Letters, 2014, 104, 073501.	3.3	50
6	DyScO3 buffer layer for a performing metal-ferroelectric-insulator-semiconductor structure with multiferroic BiFeO3 thin film. Applied Physics Letters, 2009, 94, 142907.	3.3	42
7	Structural, electrical, and magnetic properties of chemical solution deposited Bi(Fe0.95Cr0.05)O3 thin films on platinized silicon substrates. Journal of Applied Physics, 2009, 105, .	2.5	35
8	Ferroelectric photovoltaic properties in doubly substituted (Bi0.9La0.1)(Fe0.97Ta0.03)O3 thin films. Applied Physics Letters, 2015, 106, .	3.3	35
9	Temperature dependent Raman scattering and electronic transitions in rare earth SmFeO3. Ceramics International, 2018, 44, 4198-4203.	4.8	30
10	Freestanding n-Doped Graphene via Intercalation of Calcium and Magnesium into the Buffer Layer–SiC(0001) Interface. Chemistry of Materials, 2020, 32, 6464-6482.	6.7	28
11	A graphene integrated highly transparent resistive switching memory device. APL Materials, 2018, 6, .	5.1	26
12	Unipolar resistive switching in planar Pt/BiFeO3/Pt structure. AIP Advances, 2015, 5, .	1.3	25
13	Structural and Electrical Properties of Lanthanum Gadolinium Oxide: Ceramic and Thin Films for High-k Application. Integrated Ferroelectrics, 2011, 125, 44-52.	0.7	22
14	Dielectric properties and electrical conduction of high-k LaGdO3ceramics. Journal of Applied Physics, 2012, 111, 102811.	2.5	20
15	Nonpolar resistive memory switching with all four possible resistive switching modes in amorphous LaHoO3 thin films. Journal of Applied Physics, 2015, 118, .	2.5	18
16	Optical, ferroelectric, and piezoresponse force microscopy studies of pulsed laser deposited Aurivillius Bi5FeTi3O15 thin films. Journal of Applied Physics, 2014, 116, .	2.5	17
17	Preferential grain growth and improved fatigue endurance in Sr substituted PZT thin films on Pt(111)/TiOx/SiO2/Si substrates. Journal of Alloys and Compounds, 2009, 482, 253-255.	5.5	16
18	Arrays of Si vacancies in 4H-SiC produced by focused Li ion beam implantation. Scientific Reports, 2021, 11, 3561.	3.3	16

Shojan P Pavunny

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19	Lanthanum Gadolinium Oxide: A New Electronic Device Material for CMOS Logic and Memory Devices. Materials, 2014, 7, 2669-2696.	2.9	15
20	Optical properties of amorphous high-k LaGdO3 films and its band alignment with Si. Journal of Applied Physics, 2012, 111, .	2.5	14
21	Advanced high-k gate dielectric amorphous LaGdO3 gated metal-oxide-semiconductor devices with sub-nanometer equivalent oxide thickness. Applied Physics Letters, 2013, 102, .	3.3	13
22	Properties of the new electronic device material La <scp>G</scp> dO <sub>3</sub> . Physica Status Solidi (B): Basic Research, 2014, 251, 131-139.	1.5	13
23	Advanced high-k dielectric amorphous LaGdO3 based high density metal-insulator-metal capacitors with sub-nanometer capacitance equivalent thickness. Applied Physics Letters, 2013, 102, .	3.3	12
24	On the Resistive Switching and Current Conduction Mechanisms of Amorphous LaGdO <sub>3 </sub> Films Grown by Pulsed Laser Deposition. ECS Transactions, 2013, 53, 229-235.	0.5	10
25	Structural phase transition of ternary dielectric SmGdO3: Evidence from angle dispersive x-ray diffraction and Raman spectroscopic studies. Journal of Applied Physics, 2015, 117, 094101.	2.5	9
26	Holmium hafnate: An emerging electronic device material. Applied Physics Letters, 2015, 106, .	3.3	8
27	Effect of off-center ion substitution in morphotropic lead zirconate titanate composition. Journal of Applied Physics, 2017, 121, 194102.	2.5	8
28	Si:SrTiO3-Al2O3-Si:SrTiO3 multi-dielectric architecture for metal-insulator-metal capacitor applications. Applied Physics Letters, 2016, 109, 212901.	3.3	7
29	Metalorganic chemical vapor deposited buffer layer in metal–ferroelectric–insulator–semiconductor diodes. Solid State Communications, 2009, 149, 2013-2016.	1.9	6
30	Optical Dielectric Function Modeling and Electronic Band Lineup Estimation of Amorphous High-k LaGdO <sub>3</sub> Films. ECS Journal of Solid State Science and Technology, 2012, 1, N53-N57.	1.8	6
31	Optical properties and electronic band lineup on Si of amorphous zirconium modified Bi2Zn2/3Nb4/3O7 thin films. Journal of Alloys and Compounds, 2015, 644, 545-553.	5.5	6
32	Effect of La and Sc co-doping on dielectric and ferroelectric properties of PZT for energy storage capacitors. Journal of Applied Physics, 2021, 130, .	2.5	6
33	Disorder driven structural and dielectric properties of silicon substituted strontium titanate. Journal of Applied Physics, 2015, 118, .	2.5	5
34	The Thermalstability of Voltage Tunability in Pulsed Laser Deposited Ba <sub>0.6</sub> Sr <sub>0.4</sub> TiO <sub>3</sub> Thin Films. Integrated Ferroelectrics, 2015, 166, 140-149.	0.7	5
35	Low-voltage-driven Pt/BiFeO3/DyScO3/p-Si-based metal–ferroelectric–insulator–semiconductor device for non-volatile memory. Journal of Materials Science, 2018, 53, 4274-4282.	3.7	5
36	Fabrication and Electrical Characterization of High-k LaGdO <sub>3</sub> Thin Films and Field Effect Transistors. ECS Transactions, 2011, 35, 297-304.	0.5	4

Shojan P Pavunny

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37	Cauchy-Urbach Dielectric Function Modeling of Amorphous High-k LaGdO3 Films. ECS Transactions, 2012, 45, 219-223.	0.5	4
38	Resistive Switching and Current Conduction Mechanisms in Amorphous LaLuO <sub>3</sub> Thin Films Grown by Pulsed Laser Deposition. Integrated Ferroelectrics, 2014, 157, 47-56.	0.7	3
39	Processing of Cavities in SiC Material for Quantum Technologies. Materials Science Forum, 2018, 924, 905-908.	0.3	3
40	On the doping concentration dependence and dopant selectivity of photogenerated carrier assisted etching of 4H–SiC epilayers. Electrochimica Acta, 2019, 323, 134778.	5.2	3
41	Temperature-Dependent Structural Disintegration of Delafossite CuFeO2. Materials Research Society Symposia Proceedings, 2009, 1183, 55.	0.1	1
42	Unipolar resistive switching behavior of high-k ternary rare-earth oxide LaHoO3 thin films for non-volatile memory applications. Materials Research Society Symposia Proceedings, 2015, 1729, 23-28.	0.1	1
43	Analyses of Substrate-Dependent Broadband Microwave (1–40 GHz) Dielectric Properties of Pulsed Laser Deposited Ba0.5Sr0.5TiO3 Films. Crystals, 2021, 11, 852.	2.2	1
44	Nonvolatile Resistive Memory Switching in Amorphous LaGdO3 Thin Films. Materials Research Society Symposia Proceedings, 2013, 1562, 1.	0.1	0
45	Analysis of Leakage Currents through PLD Grown Ultrathin a-LaGdO3 Based High-k Metal Gate Devices. Materials Research Society Symposia Proceedings, 2013, 1561, 1.	0.1	Ο
46	Properties of the new electronic device material LaGdO3(Phys. Status Solidi B 1/2014). Physica Status Solidi (B): Basic Research, 2014, 251, n/a-n/a.	1.5	0
47	Impact of Processing on Photoluminescence Properties of 4H-SiC for Potential Qubit Applications. ECS Meeting Abstracts, 2017, , .	0.0	Ο
48	Dielectric and Ferroelectric Properties of Rare Earth Doped Lead Zirconate Titanate Ceramics. ECS Meeting Abstracts, 2018, , .	0.0	0
49	Effect of Zr Substitution for Ti on BaZrxTi1â^'XO3 Thin Films for Energy Storage Applications. ECS Meeting Abstracts, 2018, ,	0.0	0
50	Photoelectrochemical Properties of p- and n- Type 4H-SiC Epilayers: Doping Concentration Dependence and Dopant Selectivity. ECS Meeting Abstracts, 2018, , .	0.0	0